

MOS FIELD EFFECT TRANSISTOR μ PA1854

P-CHANNEL MOS FIELD EFFECT TRANSISTOR FOR SWITCHING

DESCRIPTION

The μ PA1854 is a switching device which can be driven directly by a 2.5-V power source.

The μ PA1854 features a low on-state resistance and excellent switching characteristics, and is suitable for applications such as power switch of portable machine and so on.

FEATURES

- Can be driven by a 2.5-V power source
- · Low on-state resistance

 $R_{DS(on)1} = 60 \text{ m}\Omega$ MAX. (Vgs = -4.5 V, ID = -1.5 A)

 $R_{DS(on)2} = 70 \text{ m}\Omega \text{ MAX.}$ (Vgs = -4.0 V, ID = -1.5 A)

 $R_{DS(on)3} = 105 \text{ m}\Omega \text{ MAX.} \text{ (Vgs} = -2.5 \text{ V, ID} = -1.5 \text{ A)}$

Built-in G-S protection diode against ESD

ORDERING INFORMATION

PART NUMBER	PACKAGE
μPA1854GR-9JG	Power TSSOP8

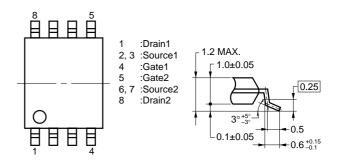
ABSOLUTE MAXIMUM RATINGS (T_A = 25°C)

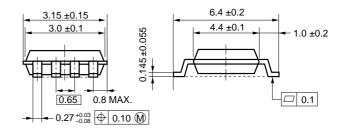
Drain to Source Voltage	Voss	-12	V
Gate to Source Voltage	Vgss	-10/+5	V
Drain Current (DC)	ID(DC)	∓3.0	Α
Drain Current (pulse) Note1	D(pulse)	∓12	Α
Total Power Dissipation Note2	Рт	2.0	W
Channel Temperature	Tch	150	°C
Storage Temperature	Tstg	-55 to +150	°C

Notes 1. PW \leq 10 μ s, Duty Cycle \leq 1 %

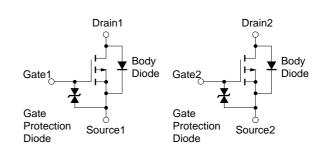
2. Mounted on ceramic substrate of 5000 mm² x 1.1 mm

PACKAGE DRAWING (Unit: mm)





EQUIVALENT CIRCUIT



Remark The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

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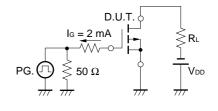
ELECTRICAL CHARACTERISTICS (T_A = 25 °C)

CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Drain Cut-off Current	Ipss	Vps = -12 V, Vgs = 0 V			-10	μΑ
Gate Leakage Current	Igss	$V_{GS} = \mp 10 \text{ V}, V_{DS} = 0 \text{ V}$			∓ 10	μΑ
Gate Cut-off Voltage	V _{GS(off)}	$V_{DS} = -10 \text{ V}, I_{D} = -1 \text{ mA}$	-0.5	-0.9	-1.5	V
Forward Transfer Admittance	yfs	V _{DS} = -10 V, I _D = -1.5 A	1	6.0		S
Drain to Source On-state Resistance	RDS(on)1	V _G S = -4.5 V, I _D = -1.5 A		46	60	mΩ
	RDS(on)2	Vgs = -4.0 V, ID = -1.5 A		49	70	mΩ
	RDS(on)3	V _G s = −2.5 V, I _D = −1.5 A		75	105	mΩ
Input Capacitance	Ciss	V _{DS} = -10 V		737		pF
Output Capacitance	Coss	V _G S = 0 V		322		pF
Reverse Transfer Capacitance	Crss	f = 1 MHz		195		pF
Turn-on Delay Time	td(on)	V _{DD} = -10 V		82		ns
Rise Time	tr	I _D = -1.5 A		460		ns
Turn-off Delay Time	td(off)	$V_{GS(on)} = -4.0 \text{ V}$		860		ns
Fall Time	t _f	$R_G = 10 \Omega$		1380		ns
Total Gate Charge	Q _G	V _{DD} = -10 V		8		nC
Gate to Source Charge	Qgs	ID = -3.0 A		2		nC
Gate to Drain Charge	Q _{GD}	Vgs = -4.0 V		3		nC
Diode Forward Voltage	V _{F(S-D)}	IF = 3.0 A, Vgs = 0 V		0.80		V
Reverse Recovery Time	trr	IF = 1.0 A, VGS = 0 V		29		ns
Reverse Recovery Charge	Qrr	di/dt = 50 A/μs		6		nC

TEST CIRCUIT 1 SWITCHING TIME

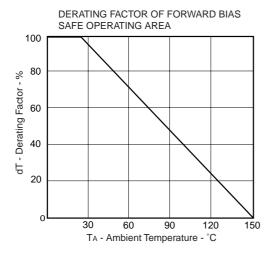
PG. $\bigcap_{RG} R_G = 10 \Omega$ V_{DD} V_{GS} $V_{Mave Form}$ $V_$

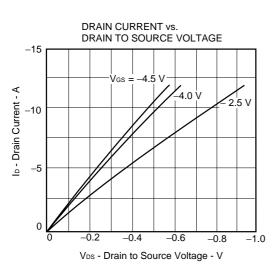
TEST CIRCUIT 2 GATE CHARGE

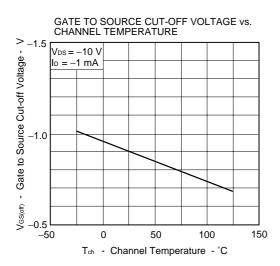


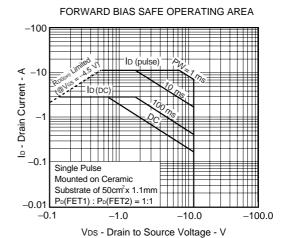


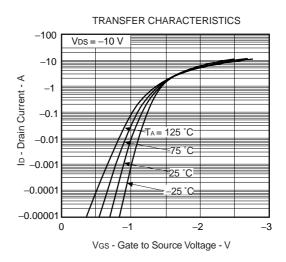
TYPICAL CHARACTERISTICS (TA = 25°C)

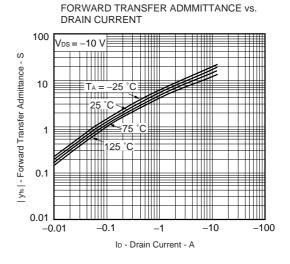






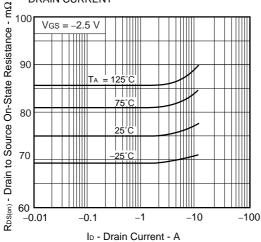




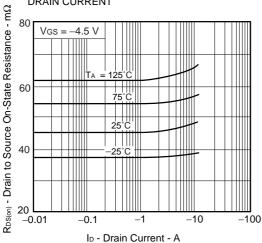


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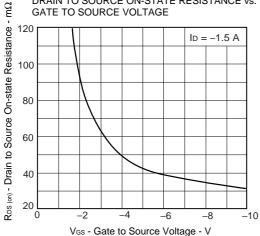
DRAIN TO SOURCE ON-STATE RESISTANCE vs. **DRAIN CURRENT**



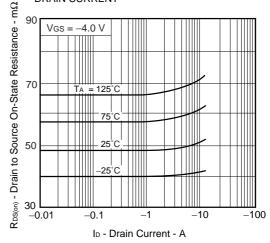
DRAIN TO SOURCE ON-STATE RESISTANCE vs. **DRAIN CURRENT**



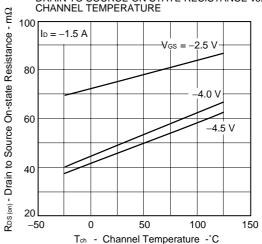
DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE



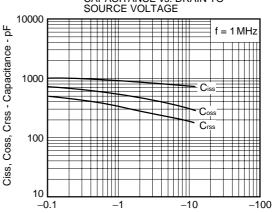
DRAIN TO SOURCE ON-STATE RESISTANCE vs. **DRAIN CURRENT**



DRAIN TO SOURCE ON STATE RESISTANCE vs. CHANNEL TEMPERATURE

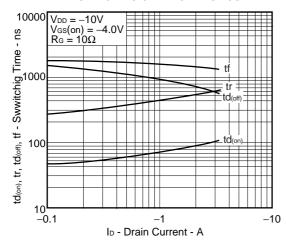


CAPACITANCE vs. DRAIN TO SOURCE VOLTAGE

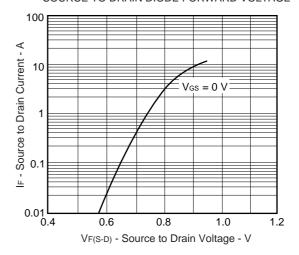


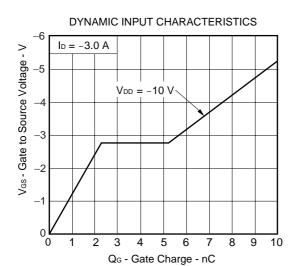
V_{DS} - Drain to Source Voltage - V

SWITCHING CHARACTERISTICS

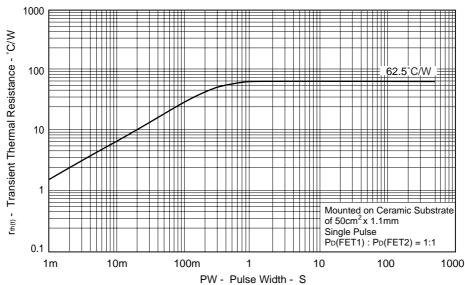


SOURCE TO DRAIN DIODE FORWARD VOLTAGE





TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH



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[MEMO]

NEC μ PA1854

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